## Notice of References Cited Application/Control No. 10/791,669 Examiner John P. Sheehan Applicant(s)/Patent Under Reexamination SHIRAISHI ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,066,978 B2	06-2006	Waki et al.	75/348
*	В	US-6,994,895 B2	02-2006	Hattori et al.	427/599
*	С	US-2005/0106487 A1	05-2005	Harada et al.	430/108.1
*	D	US-6,827,968 B2	12-2004	Naoe, Koji	427/122
*	E	US-2004/0033357 A1	02-2004	Hattori et al.	428/379
*	F	US-2003/0219669 A1	11-2003	Yamashita et al.	430/109.4
*	G	US-2003/0165759 A1	09-2003	Suzuki et al.	430/108.4
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	α					
	R					
	s					
	Т				,	

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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